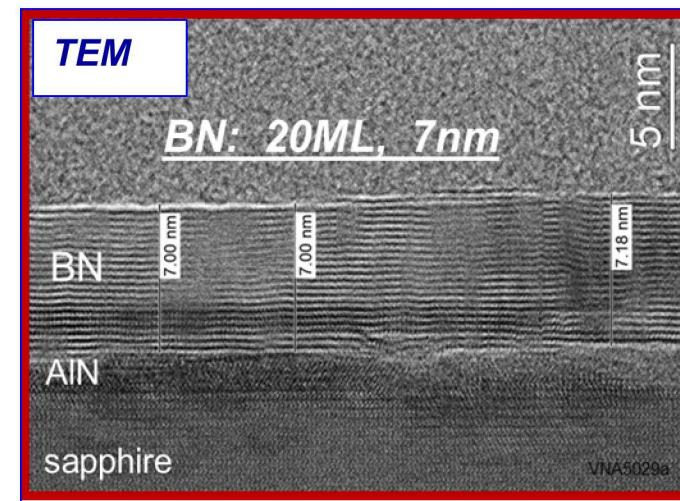
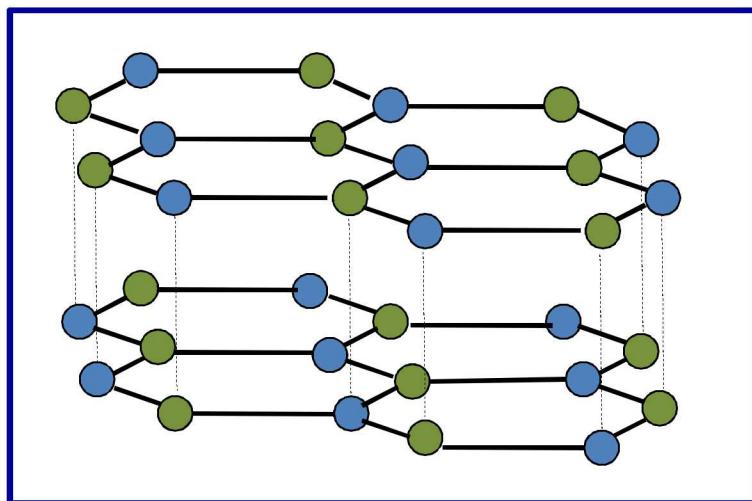


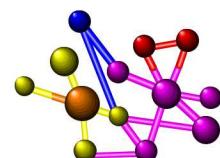
Growth of hBN by High-Temperature Metal-organic Chemical Vapor Deposition

A. Rice, M. Crawford, A. Allerman, & P. Sharps

Sandia National Laboratories, Albuquerque, NM 87185



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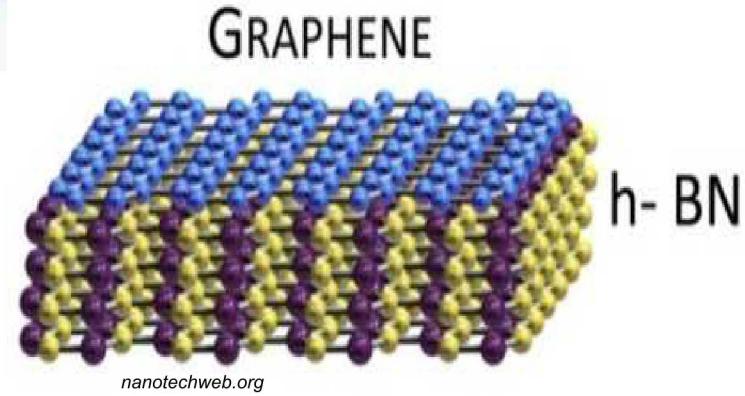


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Background - Why hBN?

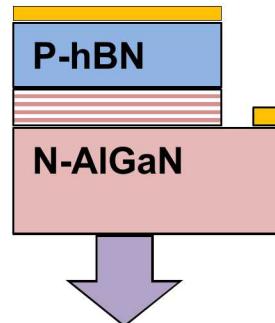
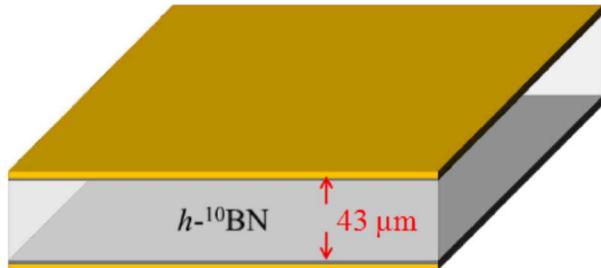
2D applications

- Dielectric substrate for high mobility graphene
- Stacked monolayers w/graphene a “circuit board” for TMDs
- Encapsulant for quantum Hall devices
- Single photon emitters, gas sensing, hyperbolic optics

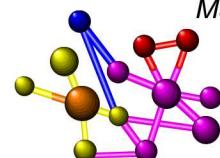
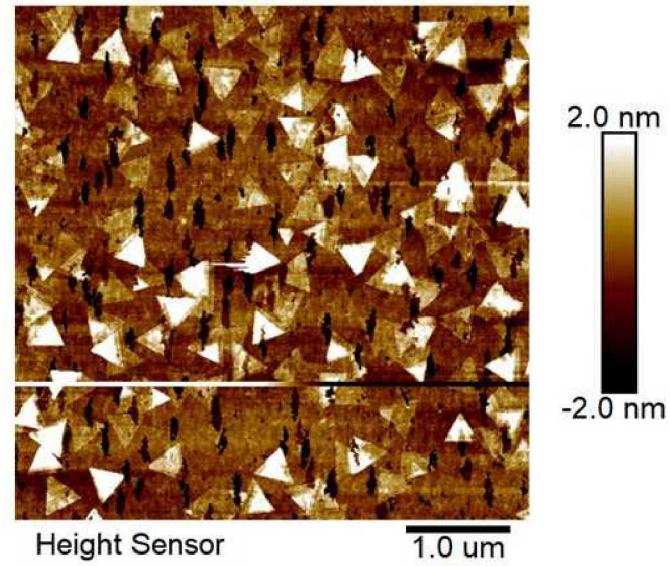


Bulk applications

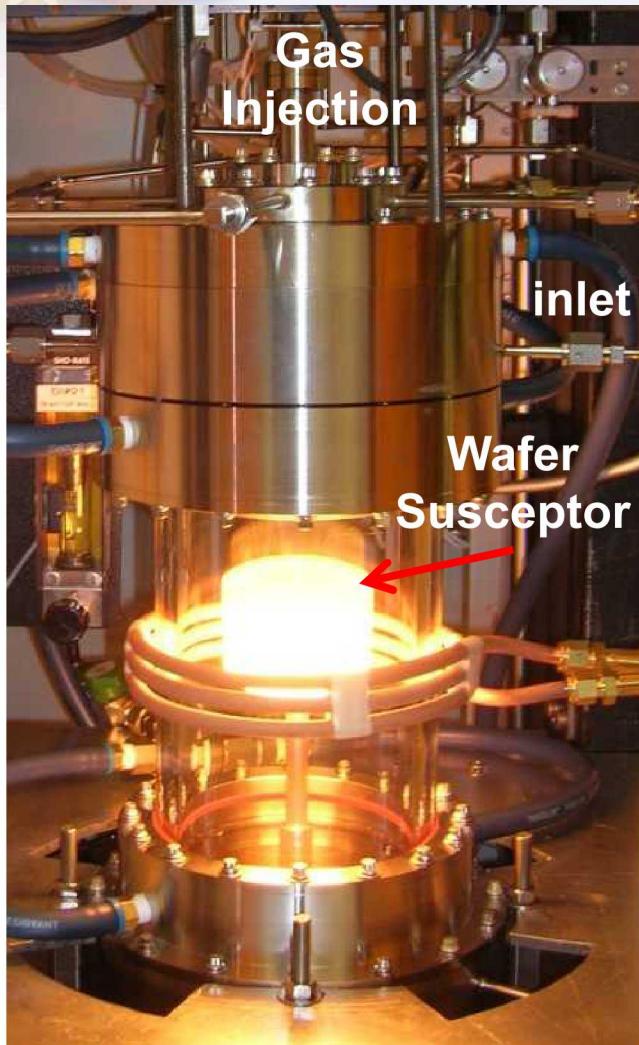
- Thermal neutron detection
- UV optoelectronics



Mono- and multi-layer WSe₂ grown on hBN

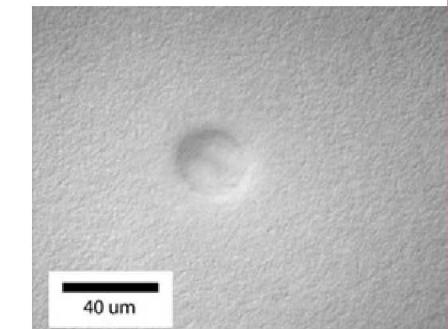


High Temperature MOCVD System

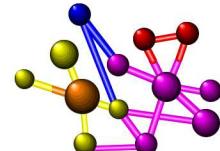


- Advantages of HT growth
 - Cold walled, RF heated up to 1900°C
 - Increased surface mobility of Group-III atoms
- Continuous Growth (TEB + NH₃)
 - Temperature: 1200 – **1600** - 1800°C
 - Pressure: 50 torr
 - NH₃: 0.1 – **2** - 5 slpm
 - TEB: **12** μ moles/min
 - Carrier gas: N₂ Diluent gas: H₂
- Continuous Growth (Borazine)
 - Temperature: 1300 – **1600** - 1700°C
 - Pressure: 50 torr
 - Borazine: **0.06 – 3.6** μ moles/min
 - Carrier & diluent gas: N₂
- Substrates
 - Sapphire & SiC

40 nm thick visibly transparent hBN film on SiC substrate w/defect

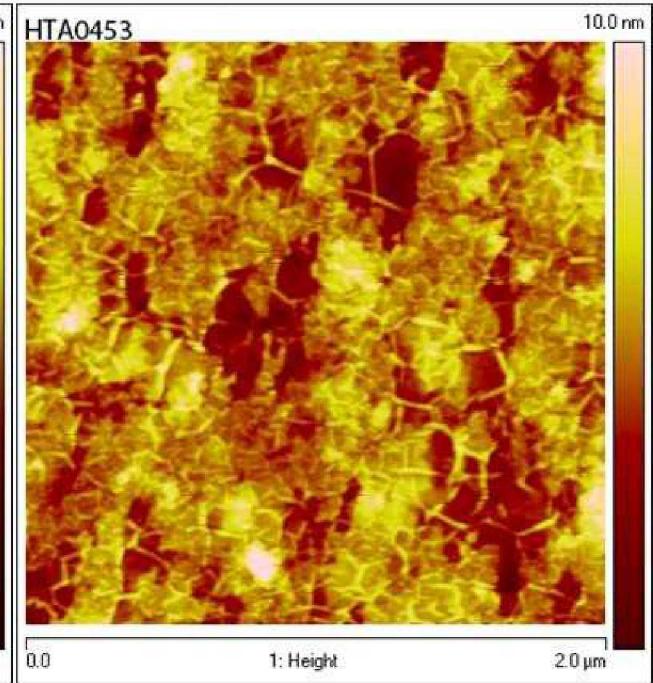
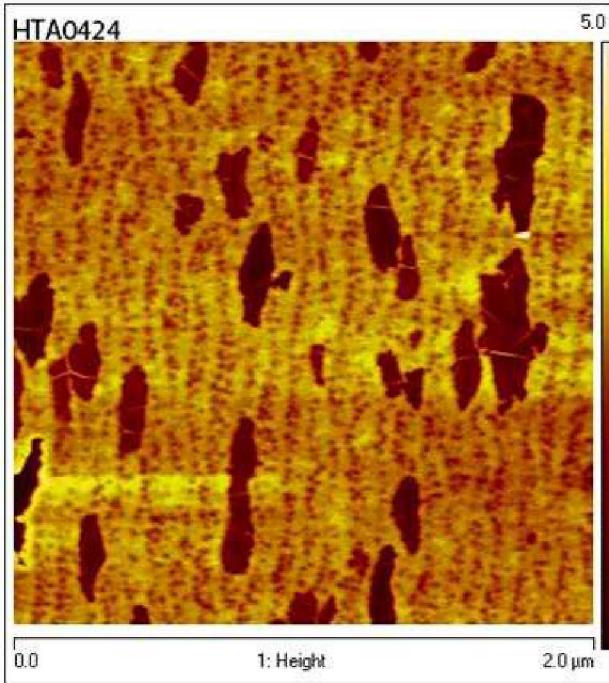
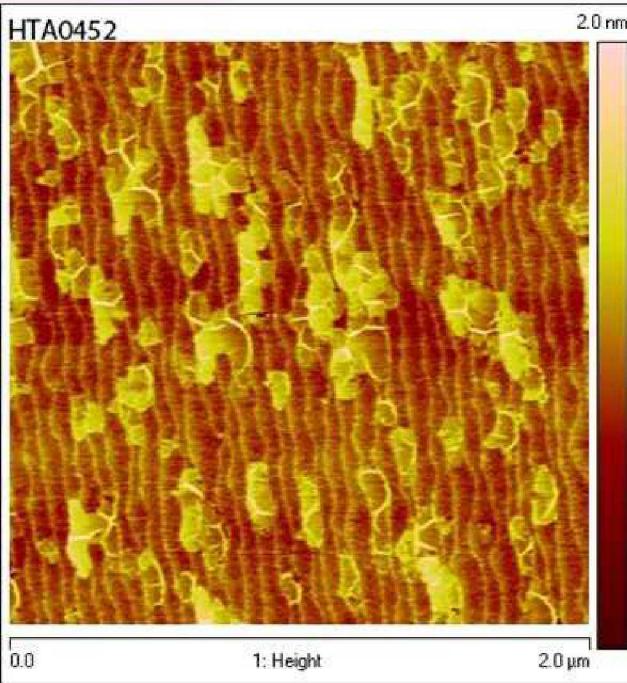


Reactor Design from Prof. Zlatko Sitar (NC State)



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hBN Monolayer Growth

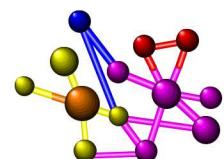


<1 monolayer
RMS roughness \sim 0.2 nm

1 to 3 monolayers
RMS roughness \sim 0.5 nm

>3 monolayers
RMS roughness $>$ 1 nm

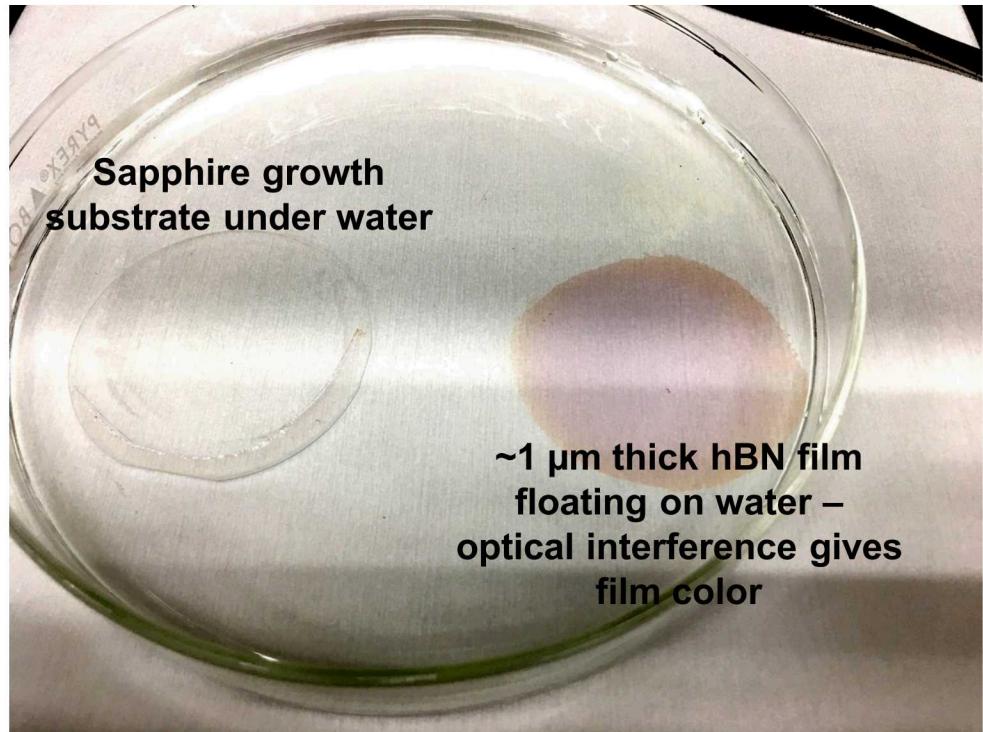
- Have developed FTIR differential reflectance technique with better than 1 monolayer thickness resolution



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Separating hBN From Sapphire

- Transfer hBN to other materials
- Allow for backside contacts
- Flatten surface, reduce strain
- Works with DI water, requires scribe at edge, “wrinkled” film, & near instantaneous lift off for 2” wafer
- Does not work with IPA – film tears apart, curls up, & stays submerged



n Detector – Fabrication & Integration

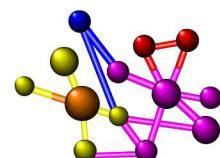
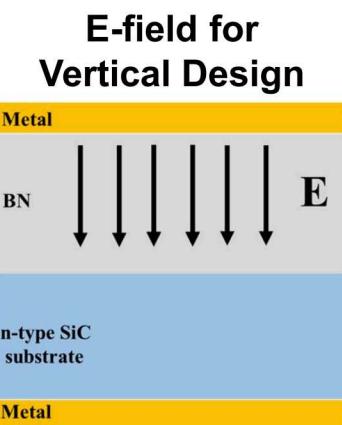
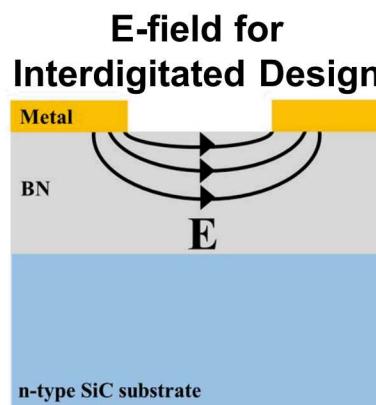
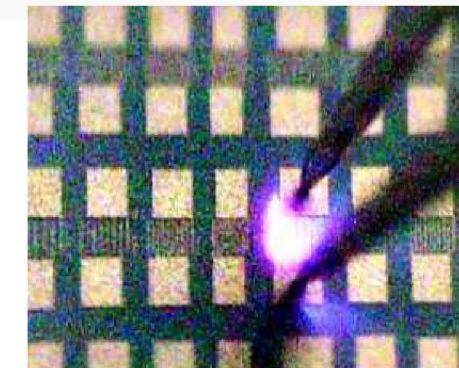
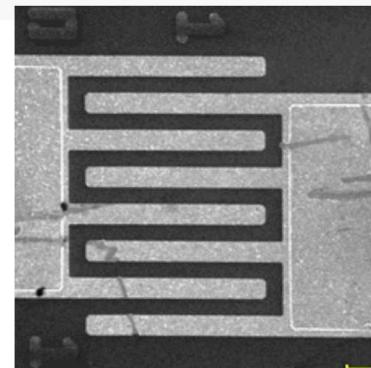
Initial test structures:

- MSM design with bulk samples and interdigitated front contacts with 2, 5, 10, 15 μm gaps
- Characterized by photocurrent and ion beam induced current (IBIC) w/100 keV Li^+
- Difficult to extract $\mu\tau$ data due to non-uniform electric fields
- Analysis suggests surface leakage

Revised design:

- Parallel plate, vertical structure to reduce $\mu\tau$ analysis complexity
- Probe volume of thicker films
- Side injected IBIC to probe thick film volumes

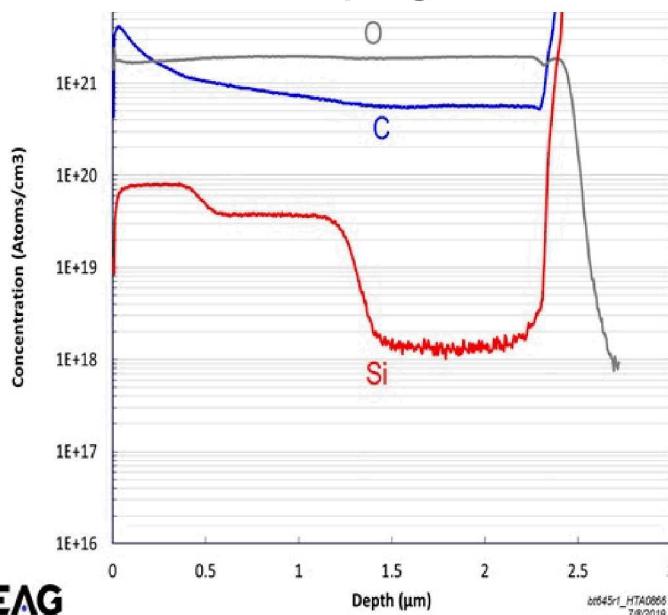
Interdigitated Design



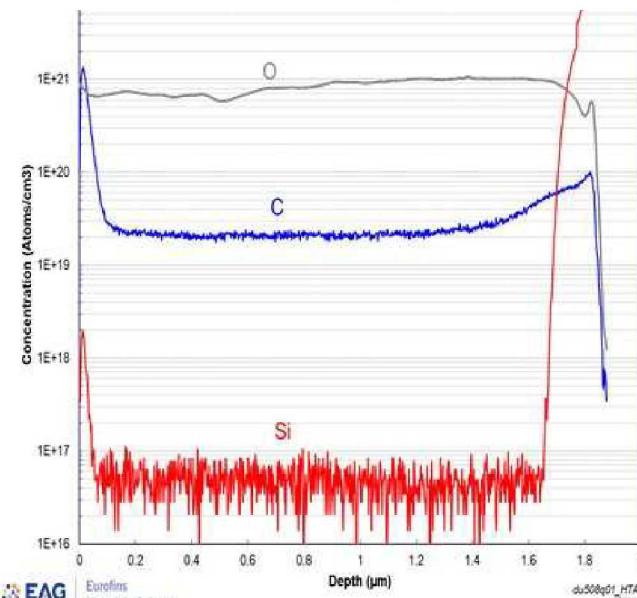
hBN Material Characterization

- SIMS analysis of hBN material indicates challenge
- Growth w/TEB & NH_3 (w/Si) has high C & O, consistent w/other results
- Borazine, w/no C, has reduced C but still too high
- Continuing to work for a reduction in C & O (e.g., higher purity precursors, alternate growth method)

Growth w/TEB $[(\text{C}_2\text{H}_5)_3\text{B}]$ & NH_3 , w/Si doping



Growth w/Borazine ($\text{B}_3\text{H}_6\text{N}_3$), no Si doping

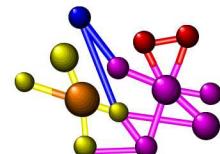




Summary

- Both monolayer and bulk hBN (40 μm) epitaxial layers demonstrated
- Demonstrated ability to remove hBN layers from sapphire
- Grown, fabricated, and tested bulk hBN for neutron testing
- Vertical, parallel plate structure preferred due to uniform E-field and avoidance of surface issues
- C and O challenges with either TEB/NH₃ and borazine precursors
- Continuing work to reduce impurities in the film growth

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